

## **Features**

- · Enhancement mode
- Low RDS(on) to minimize conduction losses
- VitoMOS<sup>®</sup> II Technology
- 100% Avalanche tested, 100% Rg tested
- Optimized Qg, Qgd, and Qgd/Qgs ratio to minimize switching losses

<b>V</b> DS	100	V
<i>R</i> DS(on), TYP@ <i>V</i> GS=10 V	2.3	mΩ
/ D(Silicon Limited)	198	Α

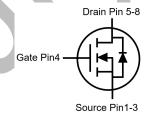








Part ID	Package Type	Marking	Packing
VSP2R8N10HS-G	PDFN5060X	2R8N10H	3000pcs/Reel



## Maximum ratings, at TA =25°C, unless otherwise specified

**Symbol Parameter** Rating Unit V(BR)DSS Drain-source breakdown voltage 100 V V Vgs Gate-source voltage ±20 Diode continuous forward current (Silicon limited) Tc = 25°C IS 198 Α Continuous drain current @VGS=10V (Silicon limited) ΙD  $T_C = 25^{\circ}C$ 198 Α Continuous drain current @VGS=10V (Silicon limited)  $T_C = 100$ °C 125 Α ΙD Pulse drain current tested ① IDM  $T_C = 25^{\circ}C$ 785 Α  $T_A = 25^{\circ}C$ 22 Α IDSM Continuous drain current @VGS=10V  $T_A = 70$ °C 17 Α EAS Avalanche energy, single pulsed 2 729 mJ Tc = 25°C W 216 PDMaximum power dissipation ③ Tc = 100°C 86 W  $T_A = 25^{\circ}C$ 2.6 W **PDSM** Maximum power dissipation 4  $T_A = 70$ °C 1.7 W Operating junction and storage temperature range -55 to 150 °C T<sub>J</sub>,Ts<sub>T</sub>G

### **Thermal Characteristics**

Symbol	Parameter	Typical	Max	Unit	
Rejc	Thermal resistance, junction-to-case ⑤	0.48	0.58	°C/W	
RθJA	Thermal resistance, junction-to-ambient ⑥	40	48	°C/W	



### **Electrical Characteristics**

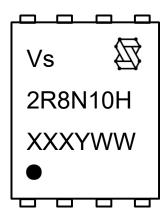
Symbol	Parameter	Condition	Min.	Тур.	Max.	Unit			
Static Electrical Characteristics @ T <sub>j</sub> =25°C (unless otherwise stated)									
V(BR)DSS	Drain-source breakdown voltage	Vgs=0V, ID=250uA	100			V			
Inco	Zero gate voltage drain current(Tj=25℃)	VDS=100V,VGS=0V			1	μΑ			
IDSS	Zero gate voltage drain current(Tj=125℃)⑦	V <sub>D</sub> s=100V,V <sub>G</sub> s=0V			100	μΑ			
IGSS	Gate-body leakage current	Vgs=±20V,Vps=0V			±100	nA			
VGS(th)	Gate threshold voltage	VDS=VGS,ID=250µA	2.7	3.2	3.7	V			
RDS(on)	Drain-source on-state resistance ®	V <sub>G</sub> s=10V, I <sub>D</sub> =40A (T <sub>j</sub> =100°C)⑦		2.3	2.8	mΩ mΩ			
GFS	Forward transconductance	Vps=5V, Ip=40A		66		S			
Dynamic	Electrical Characteristics @ Τ <sub>j</sub> = 25°C (ι	ınless otherwise s	tated)						
Ciss	Input capacitance ⑦		-	3965		pF			
Coss	Output capacitance ⑦	V <sub>DS</sub> =50V,V <sub>GS</sub> =0V, f=100KHz		1370		pF			
Crss	Reverse transfer capacitance ⑦	1-1001412		40		pF			
Rg	Gate resistance	f=1MHz		1.4		Ω			
Qg	Total gate charge ⑦	5000		63		nC			
Qgs	Gate-source charge ⑦	VDS=50V,ID=40A, VGS=10V		20		nC			
Qgd	Gate-drain charge ⑦	180 181		16		nC			
Switching	Characteristics ⑦			-					
Td(on)	Turn-on delay time	\/50\/		17		ns			
Tr	Turn-on rise time	VDD=50V, ID=40A,		41		ns			
Td(off)	Turn-off delay time	Rg=3Ω,		34		ns			
Tf	Turn-off fall time	Vgs=10V		22		ns			
Source- D	Source- Drain Diode Characteristics@ T <sub>i</sub> = 25°C (unless otherwise stated)								
VsD	Forward on voltage	Isp=40A,Vgs=0V		0.80	1	V			
Trr	Reverse recovery time ⑦	VDD=50V,		56		ns			
Qrr	Reverse recovery charge ⑦	Isd=40A, VGS=0V di/dt=100A/µs		54		nC			

## NOTE:

- ① Single pulse; pulse width ≤ 100µs.
- ② This value is based on starting TJ =  $25^{\circ}$ C, L = 0.5mH, Rg =  $25\Omega$ , IAS = 54A, VGS = 10V; 100% FT tested at L = 0.5mH, IAS = 35A.
- ③ The power dissipation Pd is based on Tj(max), using junction-to-case thermal resistance RθJC.
- $\textcircled{4} \ \, \text{The power dissipation Pdsm is based on Tj(max), using junction-to-ambient thermal resistance R\theta JA. }$
- (5) Thermal resistance from junction to soldering point (on the exposed drain pad). These tests are performed on a cool plate.
- (6) These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA=25°C.
- (7) Guaranteed by design, not subject to production testing.
- 8 Pulse width ≤ 380µs; duty cycle≤ 2%.



## **Marking Information**



1st line: Vergiga Code (Vs), Vergiga Logo

2nd line: Part Number (2R8N10H)
3rd line: Date code (XXXYWW)

XXX: Wafer Lot Number Code, code changed with Lot Number

Y: Year Code, refer to table below

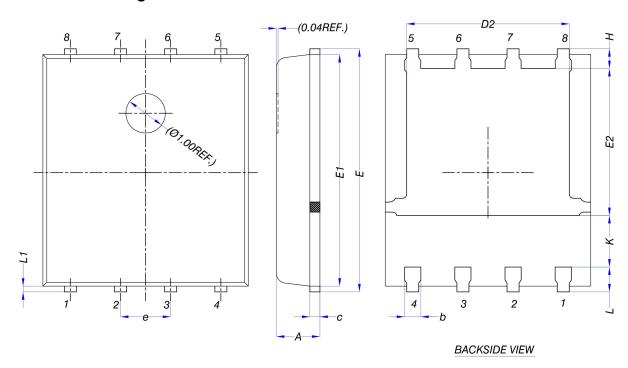
WW: Week Code (01 to 53)

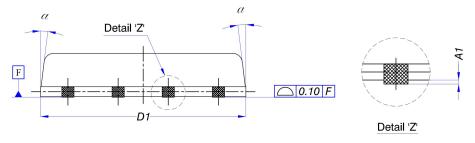
Code	С	D	Е	F	G	Н	J	К	٦	M	N	Р	Q	R	S	Т
Year	2015	2016	2017	2018	2019	2020	2021	2022	2023	2024	2025	2026	2027	2028	2029	2030

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# PDFN5060X Package Outline Data





Cumbal	DIMENSIONS ( unit : mm )							
Symbol	Min	Тур	Max					
Α	1.00	1.10	1.20					
<b>A</b> 1	0.00		0.05					
b	0.30	0.40	0.50					
С	0.20	0.25	0.30					
D1	5.00	5.20	5.40					
D2	<b>D2</b> 3.80		4.25					
E	5.95	6.15	6.35					
E1	<b>E1</b> 5.66		6.06					
E2	3.52	3.72	3.92					
е	1.27 BSC							
Н	0.40	0.50	0.60					
K	1.10							
L	0.50	0.60	0.70					
L1	0.08	0.15	0.22					
α	0°		12°					

## Notes:

- 1. Refer to JEDEC MO-240 variation AA.
- 2. Dimensions "D1" and "E1" do NOT include mold flash protrusions or gate burrs.
- 3. Dimensions "D1" and "E1" include interterminal flash or protrusion. Interterminal flash or protrusion shall not exceed 0.25mm per side.

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